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Form 1449 (Modified) **Information Disclosure Statement By Applicant** (Use Several Sheets if Necessary)	Atty Docket No. UCALP016/B02-067-1 Applicant: Kostantinos ADAM Filing Date September 30, 2003	Application No.: 10/677,136 Group 2123

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
T.P.	A	Adam et al, "*Methodology for Accurate and Rapid Simulation of Large Arbitrary 2D Layouts of Advanced Photomasks*", 21st Annual Bacus Symposium on Photomask Technology, October 3, 2001.
T.P.	B	Konstantinous Adam, "*Domain Decomposition Methods for the Electromagnetic Simulation of scattering from Three-Dimensional Structures with Applications in Lithography*", A dissertation submitted in Fall 2001 to the University of California, Berkeley.
T.P.	C	Adam et al., "*Efficient Phase Defect Modeling using Domain Decomposition Methods*", EIPBN Conference, May 2002.
T.P	D	Adam et al., "*SimplifiedModels for Edge Transitions in Rigorous Mask Modeling* ", 26th Annual Int'l Symposium on Microlithography, March 1, 2001.

Examiner	Thai Phan	Date Considered	5/29/06

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.